

**Notice of References Cited**Application/Control No.  
**09/624,691**Applicant(s)/Patent Under Reexam  
**El-Zein et al.**Examiner  
**B. William Baumeister**Art Unit  
**2815**

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	5,478,653	12/1995	Guenzer	428	446
B					
C					
D					
E					
F					
G					
H					
I					
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Country</b>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
N	52-89070	7/1977	Japan	Serizawa et al.	H01L	21/20
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>
U	Kaushik et al., "Device Characteristics of Crystalline Epitaxial Oxides on Silicon;" Device Research Conference, 2000, Conference Digest 58th DRC, pp. 17-20, June 19-21, 2000.
V	
W	
X	

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.